Shriram Ramanathan
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Professional Preparations:

Ph.D.	Materials Science and Engineering, Stanford University, 2002
M.S.	Materials Engineering, University of Houston, 1997
B.Tech.	Metallurgical Engineering, Indian Institute of Technology, Madras, 1996

Appointments:
Harvard University, Cambridge, Massachusetts, Assistant Professor of Materials Science, School of Engineering and Applied Sciences, 01/2006 – Present
Components Research, Intel Corporation, Oregon, Senior Process Engineer/Researcher, 2002-12/2005

Selected Awards:
Office of Naval Research Young Investigator Award, 2007
IBM Faculty Development Award, 2006
Divisional Recognition Award, Components Research, Intel Corporation, 2005
Ross Tucker AIME Electronic Materials Award, 2002
Graduate Student Gold Award, Materials Research Society, 2001
Distinguished Scholar Award, Microbeam Analysis Society, 2000

Synergistic Activities:
- Co-Chair, Materials and Devices for Beyond CMOS Scaling symposium, MRS Spring Meeting, San Francisco, 2008
- Co-Chair, Electronic Materials Symposium, International MRS conference, China, 2008

Selected recent publications
1. Synthesis and interfacial phenomena in ultra-thin ytrria-doped zirconia films grown by alloy oxidation under photon irradiation, M. Tsuchiya and S. Ramanathan, *Applied Physics Letters***,** 92, 033107 (2008)
2. Tunable conductivity in nanoscale Gd-doped ceria thin films, A. Karthikeyan, M. Tsuchiya, C.L. Chang and S. Ramanathan, *Applied Physics Letters,* 90, 263108 (2007)
3. Effect of intrinsic stress from a nanoscale high-dielectric constant gate oxide on carrier transport in a semiconductor channel, H.T. Wang and S. Ramanathan, *Applied Physics Letters*, 91, 012106 (2007)
4. In-situ ion scattering and X-ray photoelectron spectroscopy studies of stability and nanoscale oxidation of single crystal (100) InAs, C.L. Chang, V. Shutthanandan, S.C. Singhal and S. Ramanathan, *Applied Physics Letters*, 90, 203109 (2007)
5. X-ray absorption spectroscopy studies of vanadium oxide thin films across the phase transition boundary, D. Ruzmetov, S. Senanayake and S. Ramanathan, *Physical Review B***,** 75, 195102 (2007)